

STGW50NB60M

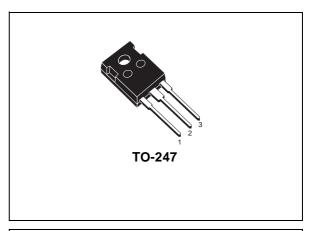
N-CHANNEL 50A - 600V - TO-247 PowerMESH™ IGBT

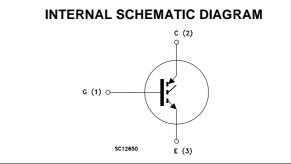
TYPE	V _{CES}	V _{CE(sat)(25°C)}	Ic
STGW50NB60M	600 V	< 1.9 V	50 A

- HIGH INPUT IMPEDANCE (VOLTAGE DRIVEN)
- LOW ON-VOLTAGE DROP (V_{CESAT})
- LOW GATE CHARGE
- HIGH CURRENT CAPABILITY



Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the Power-MESH™ IGBTs, with outstanding performances. The suffix "M" identifies a family optimized to achieve very low saturation on voltage for frequency applications <10 KHz.





APPLICATIONS

- MOTOR CONTROL
- WELDING EQUIPMENTS

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{CES}	Collector-Emitter Voltage (V _{GS} = 0)	600	V
V _{ECR}	Reverse Battery Protection	20	V
V _{GE}	Gate-Emitter Voltage	±20	V
Ic	Collector Current (continuous) at T _C = 25°C	100	А
Ic	Collector Current (continuous) at T _C = 100°C	50	А
I _{CM} (•)	Collector Current (pulsed)	400	Α
P _{TOT}	Total Dissipation at T _C = 25°C	250	W
	Derating Factor	2	W/°C
T _{stg}	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C

(ullet) Pulse width limited by safe operating area

May 2003 1/9

STGW50NB60M

THERMAL DATA

Rthj-case	Thermal Resistance Junction-case Max	0.5	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	30	°C/W
Rthc-h	Thermal Resistance Case-heatsink Typ	0.1	°C/W

ELECTRICAL CHARACTERISTICS (T_{CASE} = 25 °C UNLESS OTHERWISE SPECIFIED)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{BR(CES)}	Collector-Emitter Breakdown Voltage	$I_C = 250 \mu A, V_{GE} = 0$	600			V
I _{CES}	Collector cut-off (V _{GE} = 0)	V _{CE} = Max Rating, T _C = 25 °C V _{CE} = Max Rating, T _C = 125 °C			10 100	μA μA
I _{GES}	Gate-Emitter Leakage Current (V _{CE} = 0)	V _{GE} = ± 20 V , V _{CE} = 0			± 100	nA

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{GE(th)}	Gate Threshold Voltage	$V_{CE} = V_{GE}, I_{C} = 250 \mu\text{A}$	3	4	5	V
V _{CE(sat)}	Collector-Emitter Saturation Voltage	V _{GE} = 15V, I _C = 30 A @25°C V _{GE} = 15V, I _C = 30 A @100°C V _{GE} = 15V, I _C = 50 A @25°C V _{GE} = 15V, I _C = 50 A @100°C		1.3 1.2 1.5 1.35	1.9	V V V

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
9fs	Forward Transconductance	V _{CE} = 15 V , I _C = 18 A		22		S
C _{ies} C _{oes} C _{res}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{CE} = 25 V, f = 1 MHz, V _{GE} = 0		4500 400 70		pF pF pF
$egin{array}{c} Q_{ m g} \ Q_{ m gc} \end{array}$	Total Gate Charge Gate-Emitter Charge Gate-Collector Charge	$V_{CE} = 480 \text{ V}, I_{C} = 50 \text{ A},$ $V_{GE} = 15 \text{ V}$		231 28 97		nC nC nC
I _{CL}	Latching Current	$V_{clamp} = 480 \text{ V}$, $Tj = 125 ^{\circ}\text{C}$ $R_G = 10 \Omega$	300			А

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$V_{CC} = 480 \text{ V}, I_{C} = 50 \text{ A}$ $R_{G} = 10\Omega$, $V_{GE} = 15 \text{ V}$		45 30		ns ns
(di/dt) _{on} Eon	Turn-on Current Slope Turn-on Switching Losses	V_{CC} = 480 V, I_{C} = 50 A R_{G} =10 Ω , V_{GE} = 15 V T_{J} = 125°C		1600 800		A/µs µJ

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ELECTRICAL CHARACTERISTICS (CONTINUED)

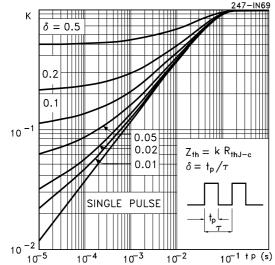
SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _c	Cross-over Time	V _{CC} = 480 V, I _C = 50 A		450		ns
$t_r(V_{off})$	Off Voltage Rise Time	$R_{GE} = 10 \Omega$, $V_{GE} = 15 V$		130		ns
t _d (off)	Delay Time			410		ns
t _f	Fall Time			300		ns
E _{off} (**)	Turn-off Switching Loss			4		mJ
E _{ts}	Total Switching Loss			4.1		mJ
t _c	Cross-over Time	V _{CC} = 480 V, I _C = 50 A		730		ns
$t_r(V_{off})$	Off Voltage Rise Time	R_{GE} = 10 Ω , V_{GE} = 15 V		265		ns
$t_{d(off)}$	Delay Time	Tj = 125 °C		565		ns
t _f	Fall Time			440		ns
E _{off} (**)	Turn-off Switching Loss			6.6		mJ
E _{ts}	Total Switching Loss			7.1		mJ

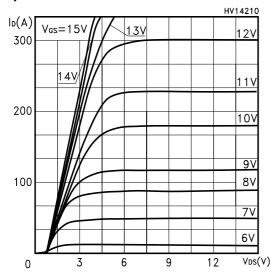
Note: 1. Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
2. Pulse width limited by max. junction temperature.

(**)Losses include Also the Tail (Jedec Standardization)

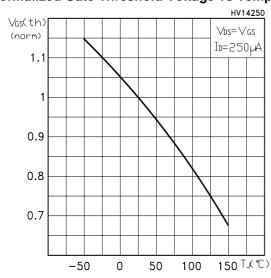
Thermal Impedance



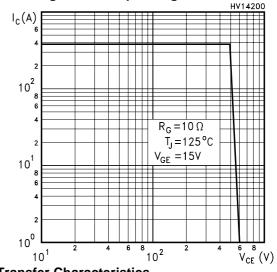
Output Characteristics



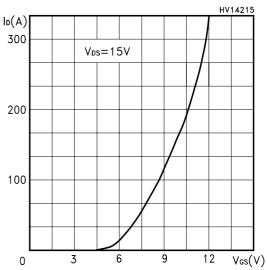
Normalized Gate Threshold Voltage vs Temp.



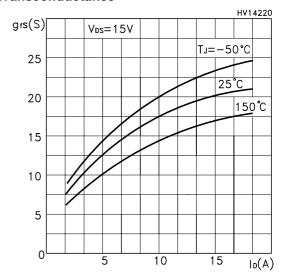
Switching Off Safe Operating Area



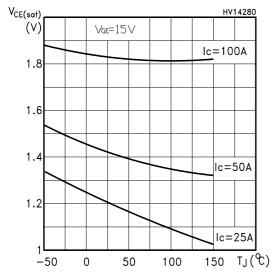
Transfer Characteristics



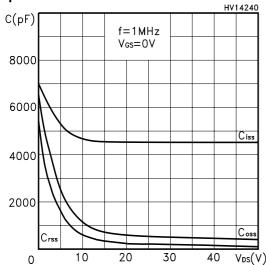
Transconductance



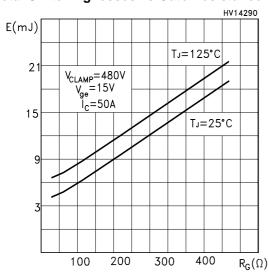
Collector-Emitter On Voltage vs Temperature



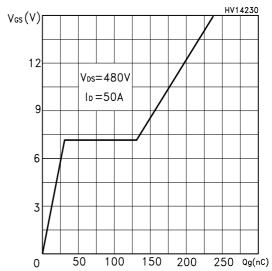
Capacitance Variations

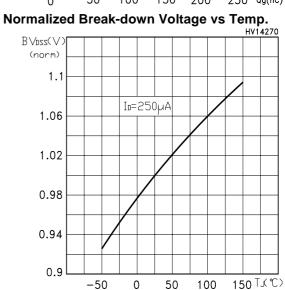


Total Switching losses vs Gate Resistance

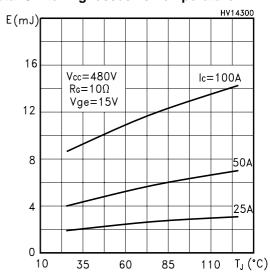


Gate-Charge vs Gate-Emitter Voltage



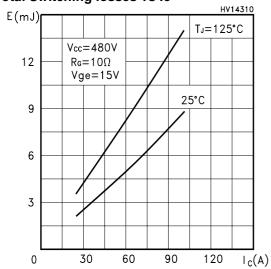


Total Switching losses vs Temperature



477.

Total Switching losses vs Ic



Collector-Emitter on Voltage vs Current

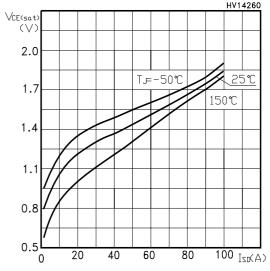


Fig. 1: Gate Charge test Circuit

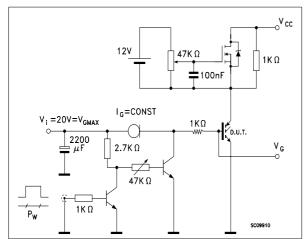
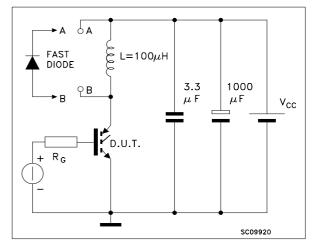
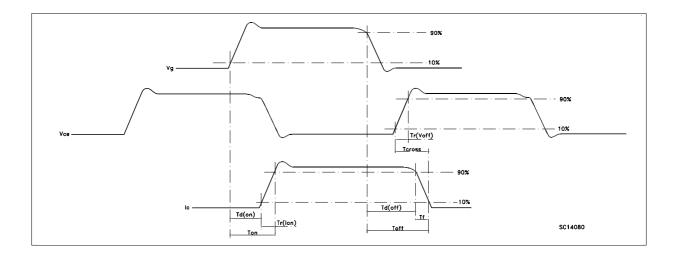


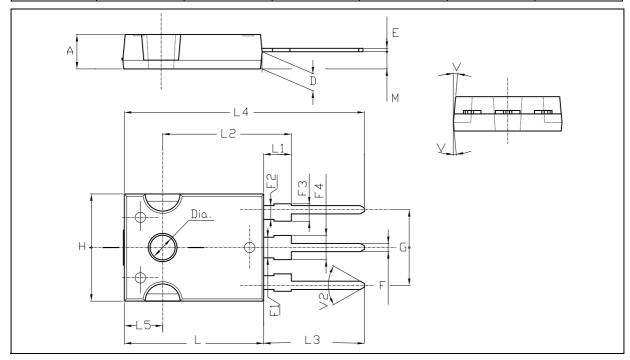
Fig. 2: Test Circuit For Inductive Load Switching





TO-247 MECHANICAL DATA

DIM		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.85		5.15	0.19		0.20
D	2.20		2.60	0.08		0.10
Е	0.40		0.80	0.015		0.03
F	1		1.40	0.04		0.05
F1		3			0.11	
F2		2			0.07	
F3	2		2.40	0.07		0.09
F4	3		3.40	0.11		0.13
G		10.90			0.43	
Н	15.45		15.75	0.60		0.62
L	19.85		20.15	0.78		0.79
L1	3.70		4.30	0.14		0.17
L2		18.50			0.72	
L3	14.20		14.80	0.56		0.58
L4		34.60			1.36	
L5		5.50			0.21	
М	2		3	0.07		0.11
V		5°			5°	
V2		60°			60°	
Dia	3.55		3.65	0.14		0.143



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